

Warpage Issue in Chip Encapsulation

STMicroelectronics
Daniela Spini

Moldex3D

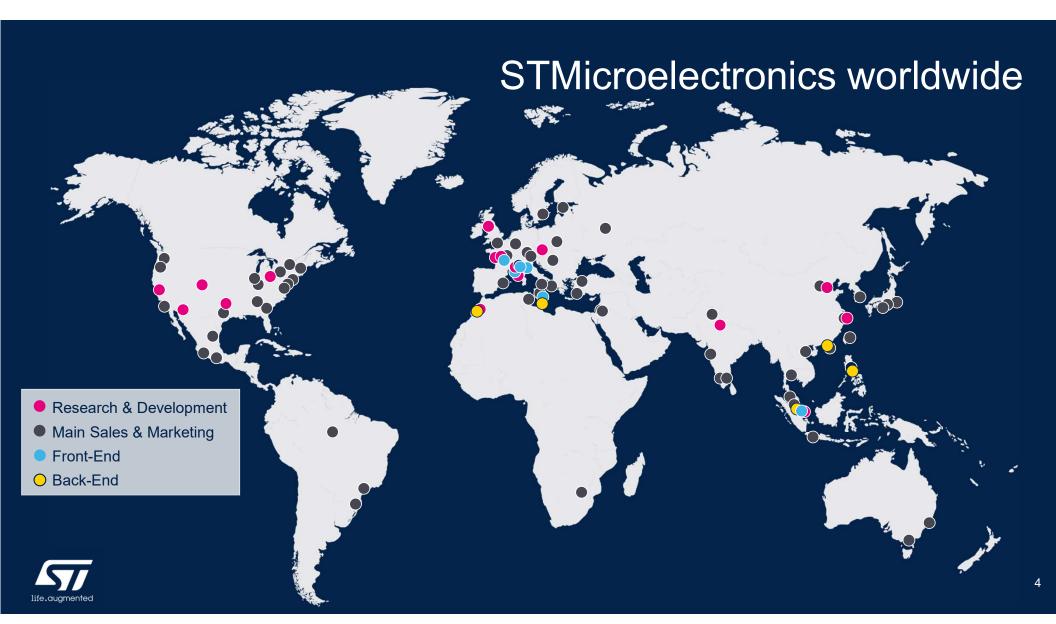
Agenda

- 1 Introduction of STMicroelectronics
- 2 IC packaging
- 3 Warpage issue
- 4 Methodology
- 5 Chip encapsulation simulations and results
- 6 Conclusion



STMicroelectronics: Beyond Semiconductor





Our technology stems from long-term strategic enablers

Smart Mobility



ST provides innovative solutions to help our customers make driving safer, greener and more connected for everyone

Power & Energy



ST technology and solutions enable customers to increase energy efficiency everywhere and support the use of renewable energy sources

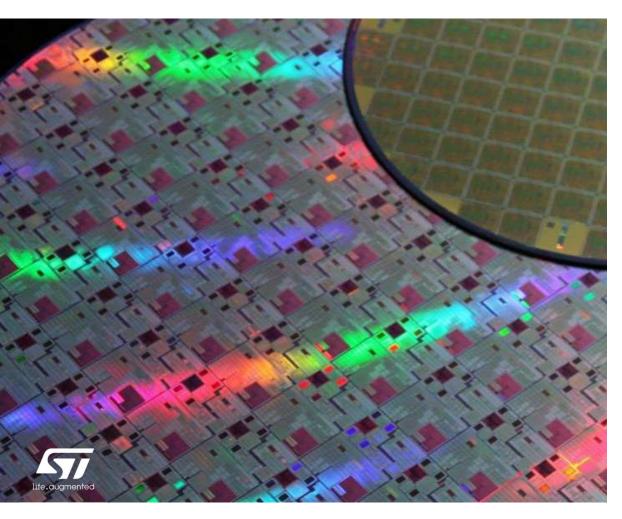
Internet of Things & 5G



ST provides sensors, embedded processing solutions, connectivity, security and power management, as well as tools and ecosystems to make development fast and easy for our customers

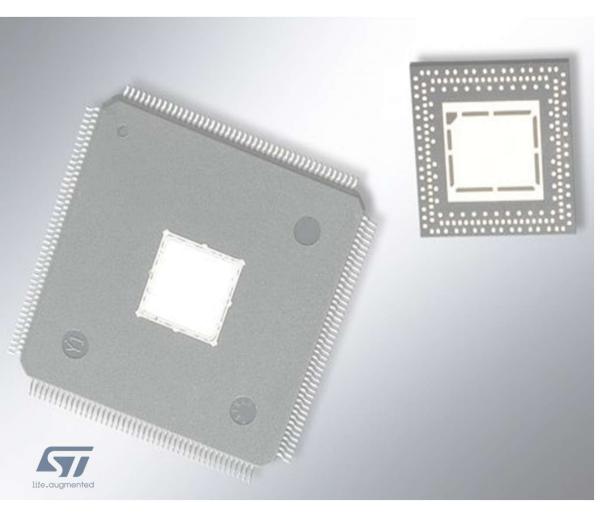


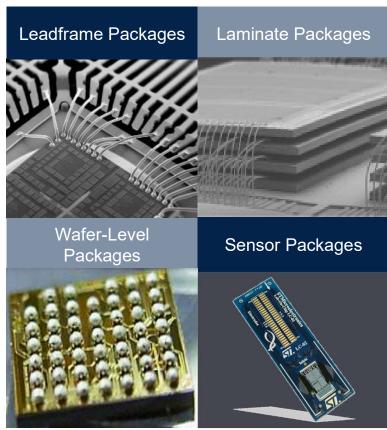
Semiconductor technologies are our foundation





Packaging technologies are our future







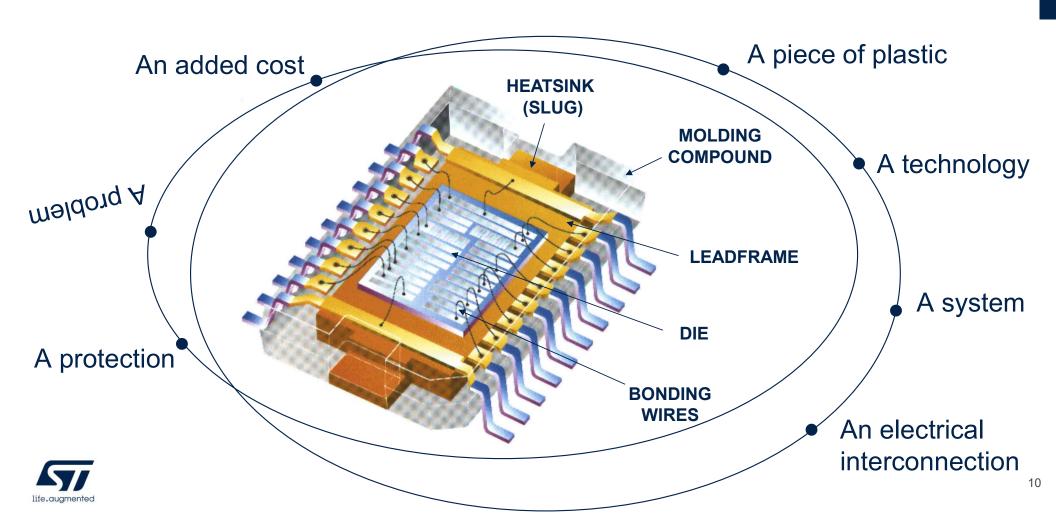
About Myself

- Modeling and Characterization Engineer
 - Advanced laboratory experiments on materials for IC packaging
 - Molding process modeling for R&D activity
 - MSc in Material and Nanotechnology Engineering

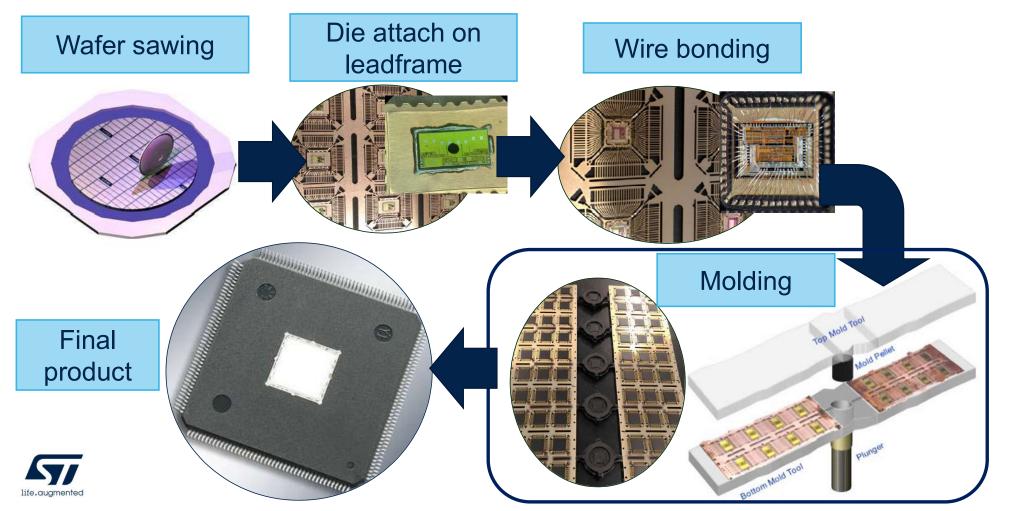
IC Packaging



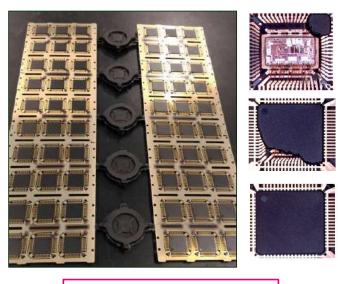
What's a package in microelectronics?



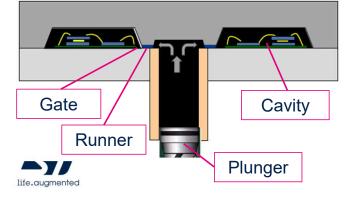
Packaging assembly process flow



Molding process



Transfer molding



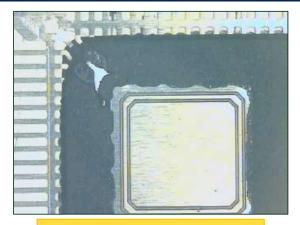
- Molding is the process of microchip encapsulation within a mold cavity by epoxy molding compound (EMC) injection
- EMC is a combination of organic (thermoset polymer) and inorganic (silica filler)

What does EMC provide?

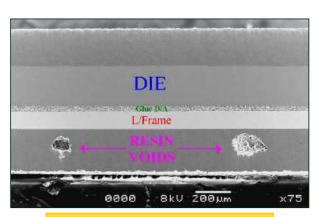
- Protection of the die from any damage and contamination
- Package structural and mechanical stability
- Create a barrier to limit the corrosion
- Low-cost manufacturing

Molding process

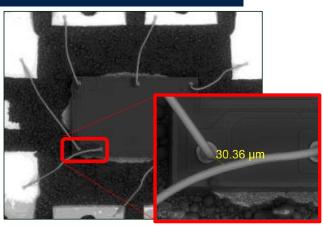
Typical reliability issues caused by molding process which led to production loss and/or customer complaint







Internal voids



Wire sweeping and crossing

It's time to predict molding defects by acting on:

Process parameters

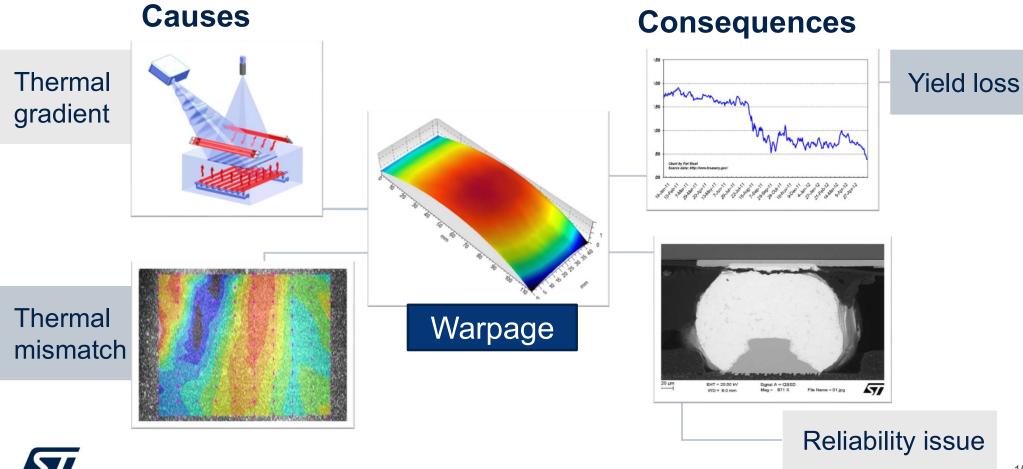




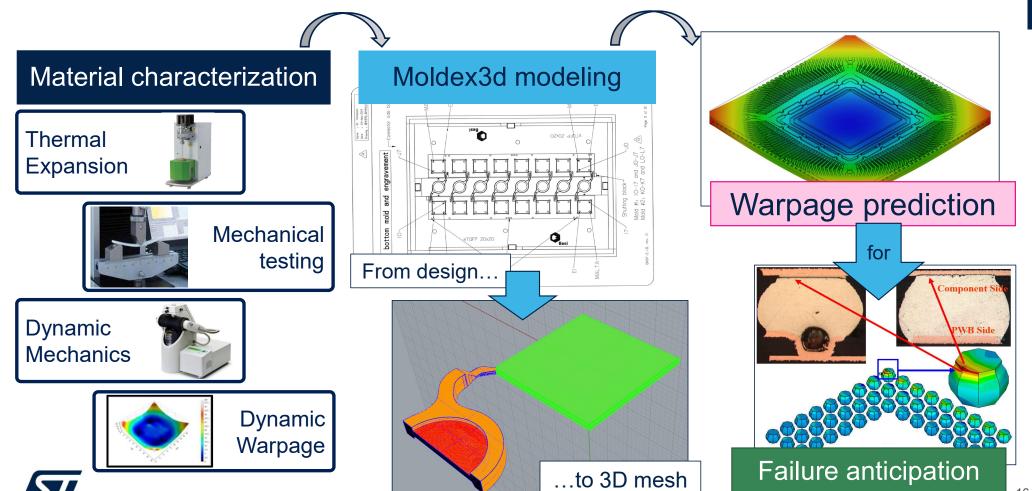
Warpage issue



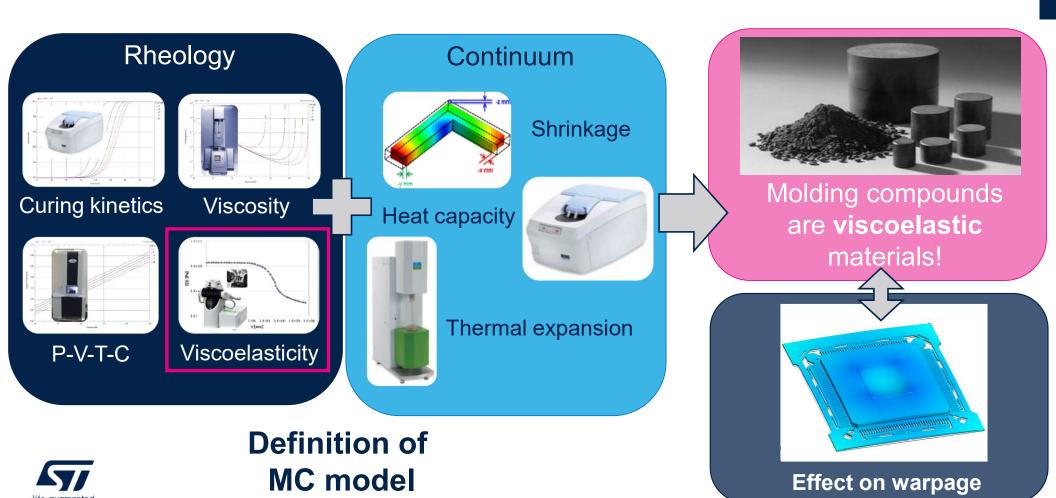
Warpage issue



How do we face it?



What we do for molding compounds?



Methodology



Viscoelasticity in few words

Material exhibiting viscous and elastic characteristics when stressed

Viscous

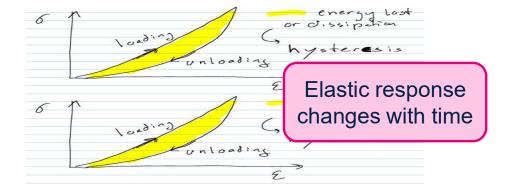
Elastic





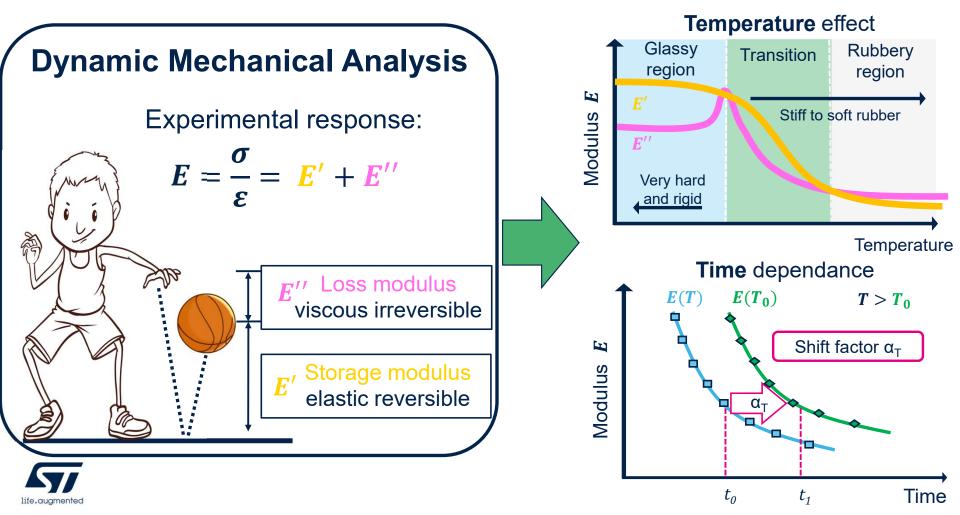




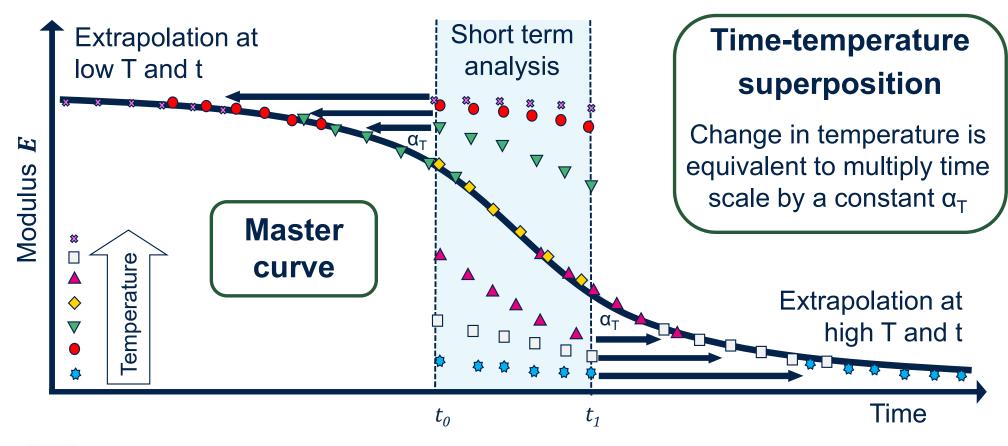




How is viscoelasticity measured?



How is viscoelasticity measured?

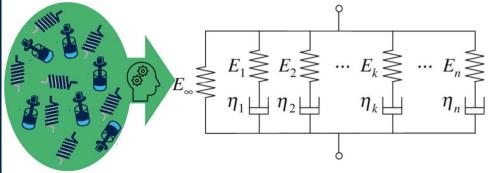


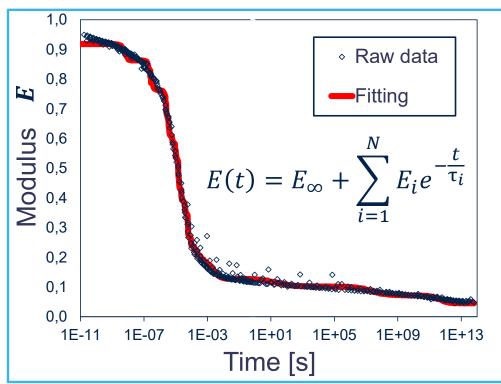


It's now easy to model...

Material model

- From DMA tests to master curve
- Fitting raw data to Prony series
- Correlation with physical models





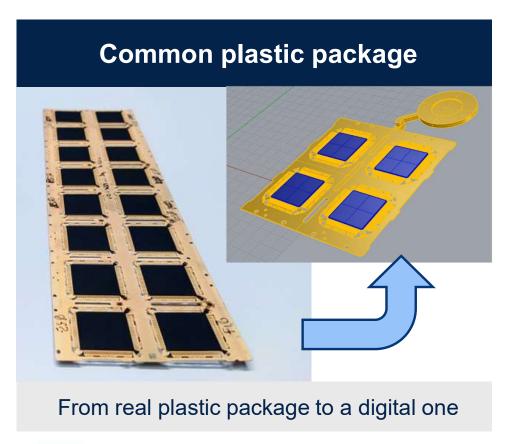


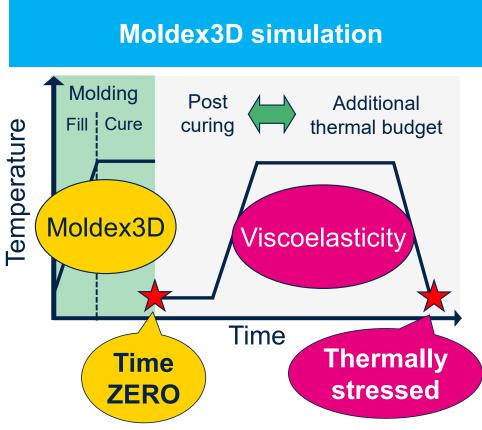
Material model is suitable for warpage analysis

Chip encapsulation simulations and results



Case study for warpage investigation







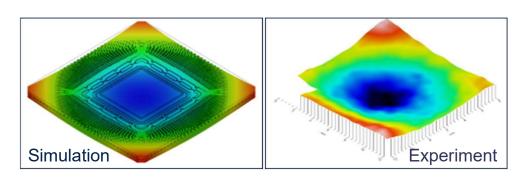


Simulation results

Filling is complete and no voids are present

→ Moldex3D

Warpage after mold

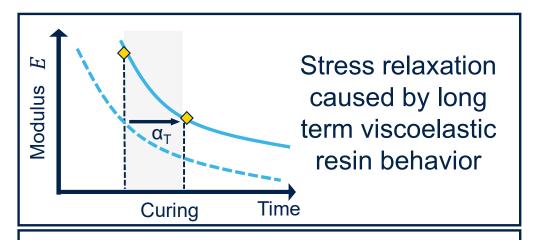


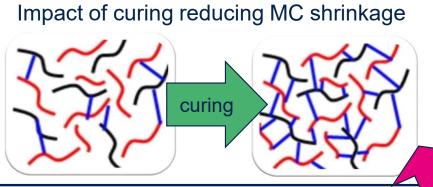
Warpage	Simulation	Experiment
Time ZERO	26.2um	24.7um

Good match, model validated!

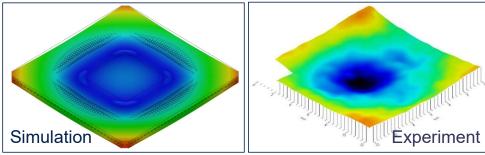


Simulation results





Warpage post mold curing



Warpage	Simulation	Experiment
After mold	26.2um	24.7um
T Stress	19.4um <	18.5um

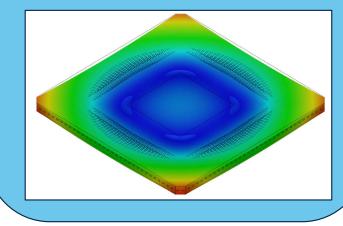
Reduction of about 25%



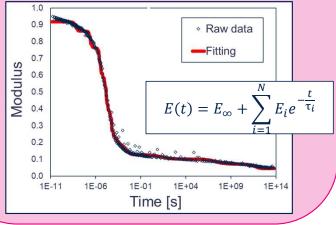
Conclusion

Thanks to Moldex3D simulation with chip encapsulation tool:

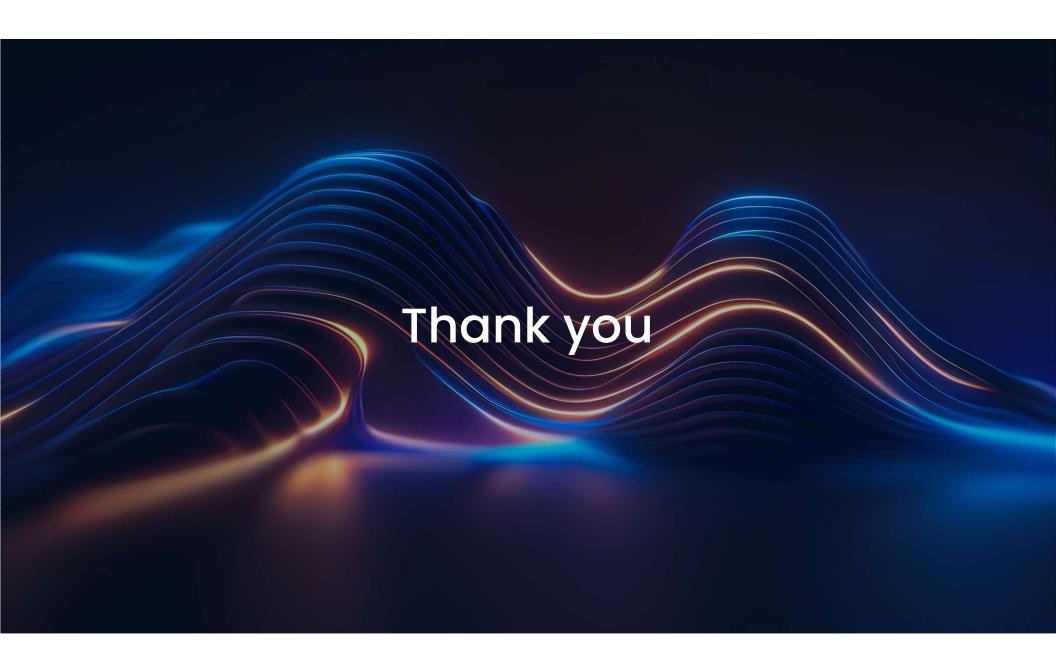
It is possible to reproduce warpage behavior of IC package in order to predict it.



It is possible to implement material properties with complex models:







Back-up slides

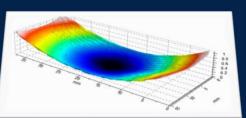


Warpage test

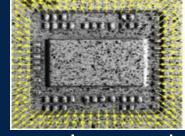
Topography and Deformation Measurement (TDM)







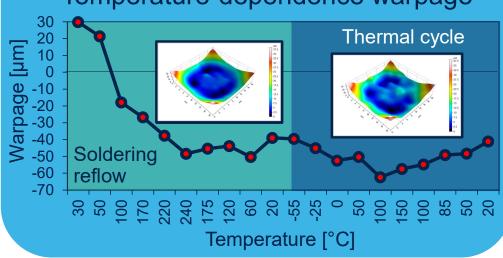
3D warpage



Thermal expansion

Application

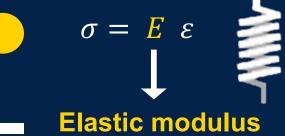
- Real-time measurements
- Overall material expansion
- Temperature-dependence warpage

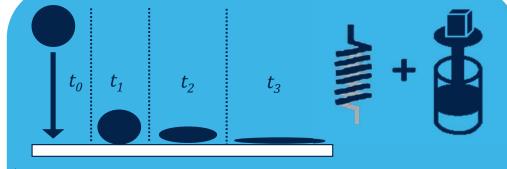




Physical interpretation







Viscoelasticity is a combination of springs and dashpots

Retarded elastic response

$$E(t) = \sum_{i=1}^{N} E_i e^{-\frac{t}{\tau_i}}$$
 Need to quantify!



 t_1

Dashpot for viscous response

 $\sigma = \frac{\eta}{\partial t} \frac{\partial \varepsilon}{\partial t}$



